

# PATENT ABSTRACTS OF JAPAN

(11)Publication number : 2001-004559

(43)Date of publication of application : 12.01.2001

(51)Int.Cl.

G01N 23/04  
H05G 1/00

(21)Application number : 11-169866

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(22)Date of filing : 16.06.1999

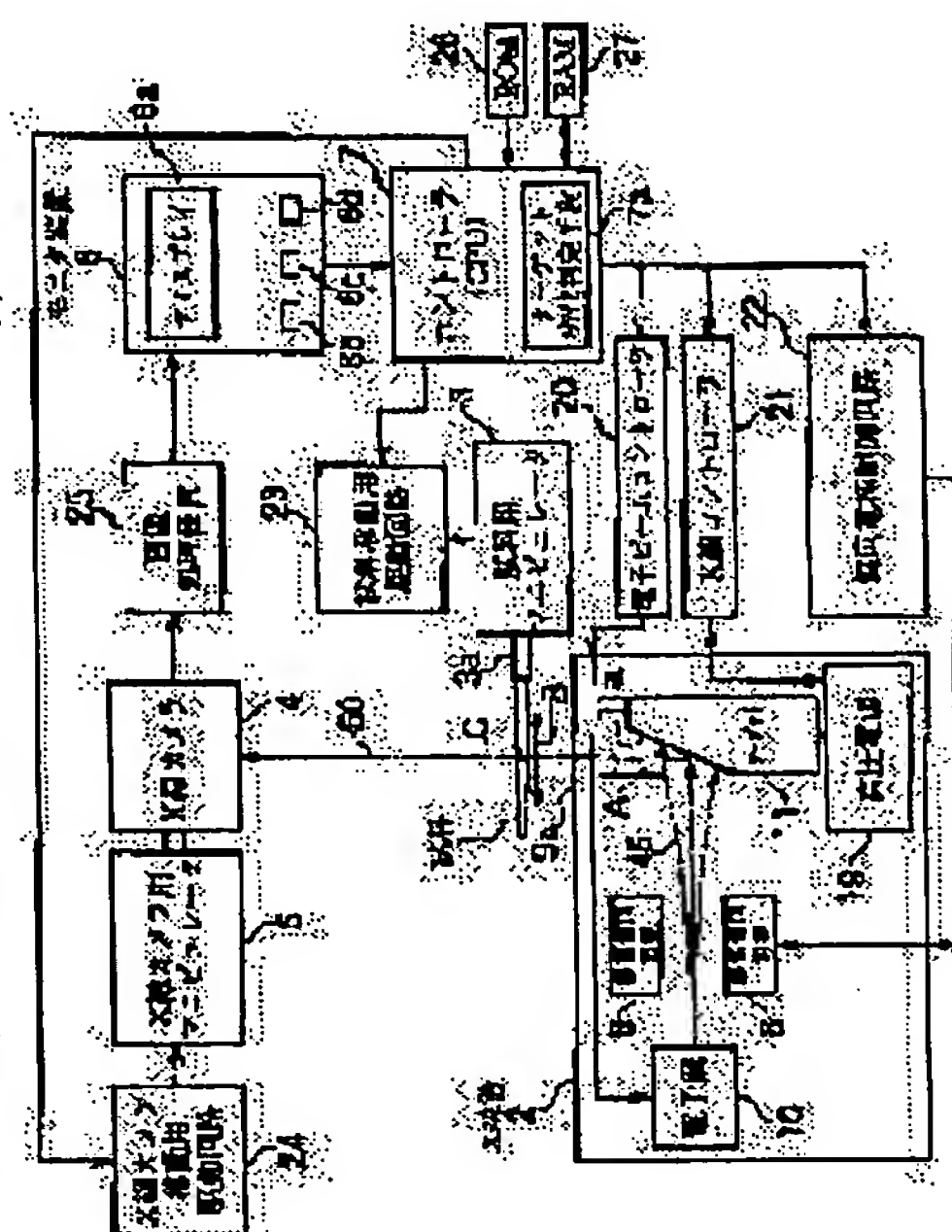
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## (54) X-RAY INSPECTING DEVICE

### (57)Abstract:

PROBLEM TO BE SOLVED: To scale the image of a sample by a new constitution.

SOLUTION: An electronic beam deflecting means 8 is controlled by a controller 7 to deflect electrons 45 heading for a target 11 in the first directions A coming close to and apart from an X-ray emergent window 9a by the electron beam deflecting means 8 and to move the location of collision of the electrons 45 against the target 11 in the first directions A. Then by changing the path length of X rays between the location of collision and a sample 1 and an X-ray image pickup device 4, it becomes possible to obtain the scaled images of the sample 1 as the output of the X-ray image pickup device 4. In addition, a sample holding/moving means 3 to hold the sample 1 is controlled by the controller 7 to move the sample 1 according to an amount corresponding to the deflection of electrons 45 in the directions B which are the moving directions of X rays 50 at the time when the electrons 45 are deflected in the first directions A by the sample holding/moving means 3 to enable the same position of the sample 1 to be irradiated with the X-rays 50, and then the scaled images including the same position of the sample 1 are obtained as the output of the X-ray image pickup device 4.



## LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

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